

Search Notes



Application/Control No.

10/690,626

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

SMALL ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	689	2/28/2006	KCC
	691		
438	692		
252	79.1		
	79.2		
	79.3		
✓ 212	79.4		
216	89	2/28/2006	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keyword search USPAT, USPG-Pub. EP, JP, IBM-TDB. Derwent, inventor search	2/28/2006	KCC